

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	49	("6295623" "6374392" "5745767" "4400663" "6311043" "5371851" "6226765" "6226765" "5226048" "5805610" "5668477" "5347518" "6233182" "6467056" "6113645" "6287765" "5859963" "6034948" "6512988" "6678643" "5696772" "5726996" "5920490" "6249891" "6061283" "6308292" "6651205" "4931723" "4994732" "5376849" "5748642" "5931953" "5931952" "5935256" "4327572" "5570383" "5604751" "6060898" "6101622" "6360343" "6377065" "6445208" "6557133" "6594609" "6668331" "5212443" "5477139" "6184048" "5371457" "4291404").pn.	US-PGPUB; USPAT	OR	ON	2004/12/09 09:42

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Most Frequently Occurring Classifications of Patents Returned  
From A Search of 10624614 on December 07, 2004

Original Classifications

7 714/724  
5 714/738  
2 324/158.1  
2 324/765  
2 713/400  
2 714/38  
2 714/718

Cross-Reference Classifications

5 324/73.1  
5 714/724  
4 365/201  
4 713/500  
4 714/738  
4 714/741  
3 324/158.1  
3 713/502  
3 714/731  
3 714/736  
3 714/742  
3 714/744  
2 703/22  
2 703/27  
2 714/39  
2 714/735

Combined Classifications

12 714/724  
9 714/738  
6 324/73.1  
5 324/158.1  
5 365/201  
5 713/500  
5 714/741  
4 714/731  
3 324/765  
3 703/22  
3 713/400  
3 713/502  
3 714/38  
3 714/736  
3 714/742  
3 714/744  
2 365/200  
2 702/117  
2 702/123  
2 703/27  
2 714/32  
2 714/39  
2 714/718  
2 714/730  
2 714/735  
2 716/6

✓ method  
①  
2 3 4

✓ app  
⑤  
6

✓ app  
⑦

method  
⑧  
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✓ CRM  
⑩

CRM  
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12

703/ 13, 14, 15, 16, 19  
714/ 28, 30, 724, 731, 738, 741, 744  
702/ 117, 119, 120, 122, 123  
716/ 4, 6

Titles of Most Frequently Occurring Classifications of Patents Returned  
From A Search of 10624614 on December 07, 2004

- 12 714/724 (7 OR, 5 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing
- 9 714/738 (5 OR, 4 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing  
714/738 ..Including test pattern generator
- 6 324/73.1 (1 OR, 5 XR)  
Class 324 : ELECTRICITY: MEASURING AND TESTING  
324/73.1 PLURAL, AUTOMATICALLY SEQUENTIAL TESTS
- 5 324/158.1 (2 OR, 3 XR)  
Class 324 : ELECTRICITY: MEASURING AND TESTING  
324/158.1 MISCELLANEOUS
- 5 365/201 (1 OR, 4 XR)  
Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL  
365/189.01 READ/WRITE CIRCUIT  
365/201 .Testing
- 5 713/500 (1 OR, 4 XR)  
Class 713 : ELECTRICAL COMPUTERS AND DIGITAL PROCESSING  
SYSTEMS: SUPPORT  
713/500 CLOCK, PULSE, OR TIMING SIGNAL GENERATION OR  
ANALYSIS
- 5 714/741 (1 OR, 4 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing  
714/738 ..Including test pattern generator  
714/741 ...Simulation
- 4 714/731 (1 OR, 3 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing  
714/726 ..Scan path testing (e.g., level sensitive scan  
design (LSSD))  
714/731 ...Clock or synchronization
- 3 324/765 (2 OR, 1 XR)  
Class 324 : ELECTRICITY: MEASURING AND TESTING  
324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF  
ELECTRIC COMPONENTS  
324/537 .Of individual circuit component or element  
324/765 ..Test of semiconductor device
- 3 703/22 (1 OR, 2 XR)  
Class 703 : DATA PROCESSING: STRUCTURAL DESIGN,  
MODELING, SIMULATION, AND EMULATION

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703/13           SIMULATING ELECTRONIC DEVICE OR ELECTRICAL  
                  SYSTEM

703/22           .Software program (i.e., performance  
                  prediction)

3   713/400       (2 OR, 1 XR)  
      Class   713 :   ELECTRICAL COMPUTERS AND DIGITAL PROCESSING  
                  SYSTEMS: SUPPORT  
      713/400       SYNCHRONIZATION OF CLOCK OR TIMING SIGNALS,  
                  DATA, OR PULSES

3   713/502       (0 OR, 3 XR)  
      Class   713 :   ELECTRICAL COMPUTERS AND DIGITAL PROCESSING  
                  SYSTEMS: SUPPORT  
      713/500       CLOCK, PULSE, OR TIMING SIGNAL GENERATION OR  
                  ANALYSIS  
      713/502       .Counting, scheduling, or event timing

3   714/38        (2 OR, 1 XR)  
      Class   714 :   ERROR DETECTION/CORRECTION AND FAULT  
                  DETECTION/RECOVERY  
      714/100       DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING  
  
      714/1         .Reliability and availability  
      714/25        ..Fault locating (i.e., diagnosis or testing)  
  
      714/37        ...Analysis (e.g., of output, state, or design)  
  
      714/38        ....Of computer software

3   714/736       (0 OR, 3 XR)  
      Class   714 :   ERROR DETECTION/CORRECTION AND FAULT  
                  DETECTION/RECOVERY  
      714/699       PULSE OR DATA ERROR HANDLING  
      714/724       .Digital logic testing  
      714/736       ..Device response compared to expected  
                  fault-free response

3   714/742       (0 OR, 3 XR)  
      Class   714 :   ERROR DETECTION/CORRECTION AND FAULT  
                  DETECTION/RECOVERY  
      714/699       PULSE OR DATA ERROR HANDLING  
      714/724       .Digital logic testing  
      714/738       ..Including test pattern generator  
      714/742       ...Testing specific device

3   714/744       (0 OR, 3 XR)  
      Class   714 :   ERROR DETECTION/CORRECTION AND FAULT  
                  DETECTION/RECOVERY  
      714/699       PULSE OR DATA ERROR HANDLING  
      714/724       .Digital logic testing  
      714/738       ..Including test pattern generator  
      714/744       ...Clock or synchronization

2   365/200       (1 OR, 1 XR)  
      Class   365 :   STATIC INFORMATION STORAGE AND RETRIEVAL  
      365/189.01    READ/WRITE CIRCUIT  
      365/200       .Bad bit

2   702/117       (1 OR, 1 XR)  
      Class   702 :   DATA PROCESSING: MEASURING, CALIBRATING, OR  
                  TESTING  
      702/108       TESTING SYSTEM

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702/117 .of circuit

2 702/123 (1 OR, 1 XR)  
 Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR  
 TESTING  
 702/108 TESTING SYSTEM  
 702/123 .Including program set up

2 703/27 (0 OR, 2 XR)  
 Class 703 : DATA PROCESSING: STRUCTURAL DESIGN,  
 MODELING, SIMULATION, AND EMULATION  
 703/23 EMULATION  
 703/27 .Compatibility emulation

2 714/32 (1 OR, 1 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
 DETECTION/RECOVERY  
 714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING  
 714/1 .Reliability and availability  
 714/25 ..Fault locating (i.e., diagnosis or testing)  
 714/32 ...Particular stimulus creation

2 714/39 (0 OR, 2 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
 DETECTION/RECOVERY  
 714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING  
 714/1 .Reliability and availability  
 714/25 ..Fault locating (i.e., diagnosis or testing)  
 714/37 ...Analysis (e.g., of output, state, or design)  
 714/39 ....Monitor recognizes sequence of events  
 (e.g., protocol or logic state analyzer)

2 714/718 (2 OR, 0 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
 DETECTION/RECOVERY  
 714/699 PULSE OR DATA ERROR HANDLING  
 714/718 .Memory testing

2 714/730 (1 OR, 1 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
 DETECTION/RECOVERY  
 714/699 PULSE OR DATA ERROR HANDLING  
 714/724 .Digital logic testing  
 714/726 ..Scan path testing (e.g., level sensitive scan  
 design (LSSD))  
 714/730 ...Addressing

2 714/735 (0 OR, 2 XR)  
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
 DETECTION/RECOVERY  
 714/699 PULSE OR DATA ERROR HANDLING  
 714/724 .Digital logic testing  
 714/735 ..Device response compared to input pattern

2 716/6 (1 OR, 1 XR)  
 Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF  
 CIRCUIT OR SEMICONDUCTOR MASK  
 716/1 CIRCUIT DESIGN

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716/4 .Testing or evaluating  
716/5 ..Design verification (e.g., wiring line  
capacitance, fan-out checking, minimum path width)  
716/6 ...Timing analysis (e.g., delay time, path  
delay, latch timing)

PLUS Search Results for S/N 10624614, Searched December 07, 2004

The Patent Linguistics Utility System (PLUS) is a USPTO automated search system for U.S. Patents from 1971 to the present. PLUS is a query-by-example search system which produces a list of patents that are most closely related linguistically to the application searched. This search was prepared by the staff of the Scientific and Technical Information Center, SIRA.

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